

Chemical Quantification of Atomic scale EDS Maps

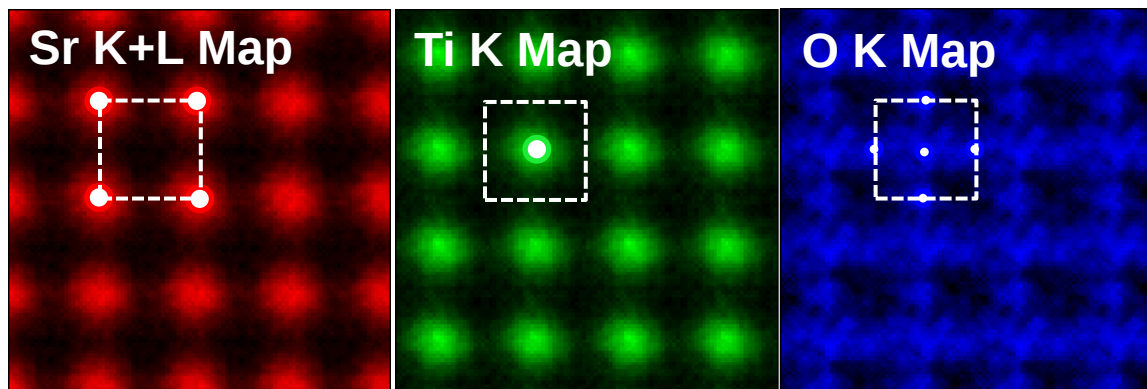
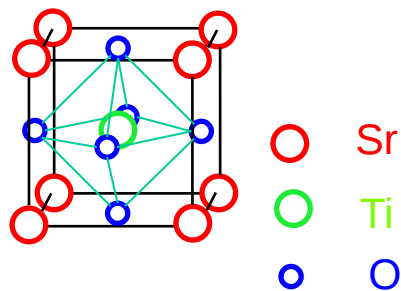
SAND2013-8738C

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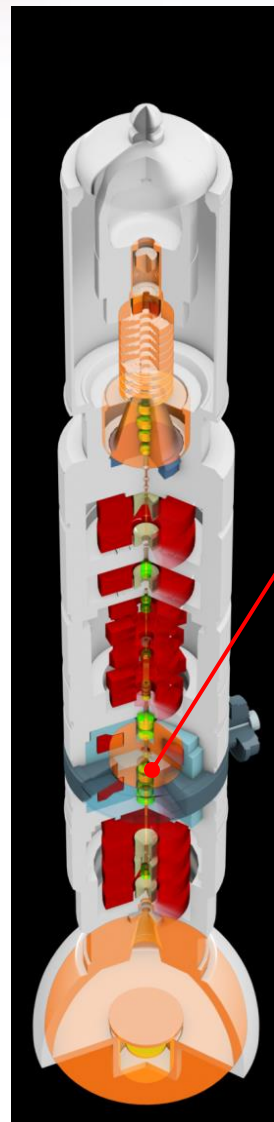
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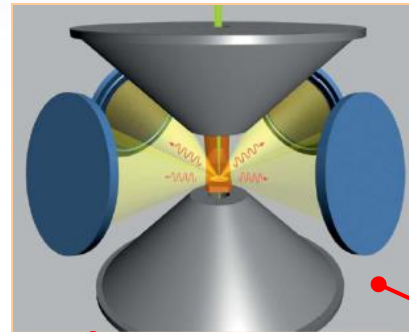
Sandia's AC-STEM capability



X-FEG

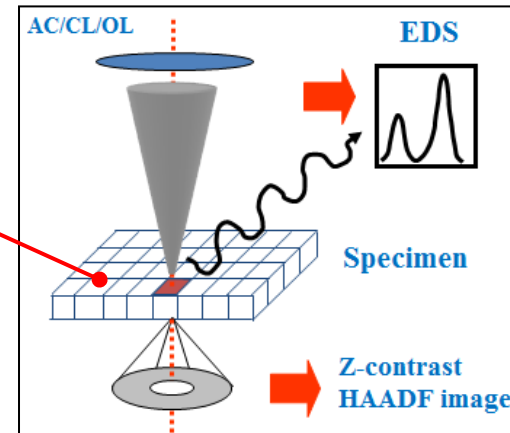
DCOR
(CEOS)

Super-X



- 4 SDD geometry
around the sample

Aberration correction and four in-lens
EDS X-ray detector technologies.

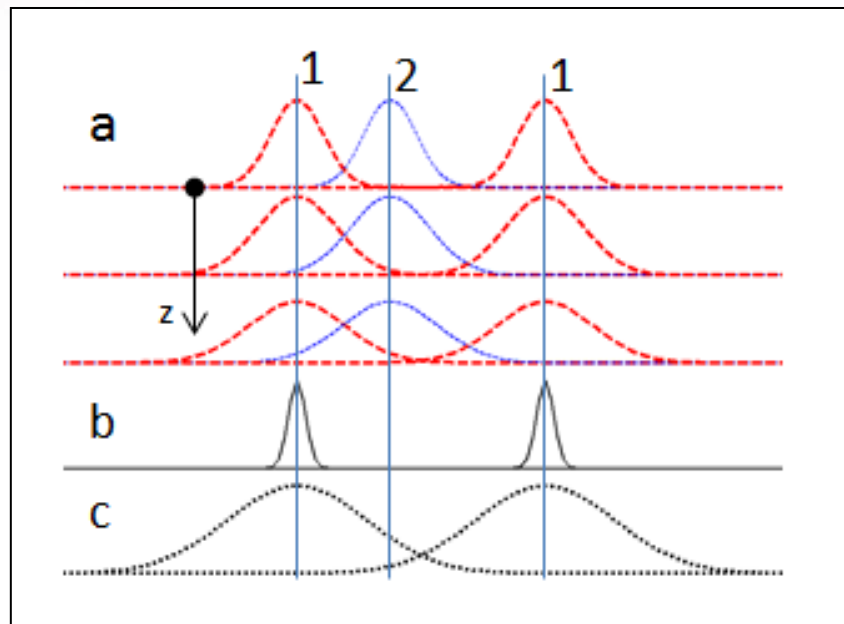


Small, intense
electron probe
+
Super efficient
EDS detector

- Sub-atomic-scale STEM imaging (80pm at 200 kV; 120pm at 80 kV)

- Atomic-scale chemical mapping by Energy X-ray Dispersive Spectroscopy (EDS)

X-ray generation process in STEM-EDS



Incoherent mode

$$\sigma(R,t) = \frac{4\pi}{h\nu J} \sum_{j=1}^J \int_0^t \int_A |\psi_j(R, \mathbf{r}_\perp, z)|^2 V(\mathbf{r}_\perp) d\mathbf{r}_\perp dz. \quad (1)$$

$$V(\mathbf{r}_\perp) = \frac{2\pi m}{h^2 t_c} \sum_n \frac{1}{k_n} |H_{n0}(\mathbf{r}_\perp)|^2, \quad (2)$$

(A.J. D'Alfonso *et al.* , Physical Review B 81, 100101 (2010))

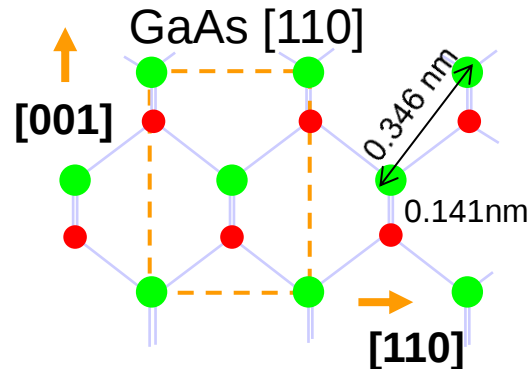
Beam broadening, channeling, de-channeling, “cross-talk”

When

- (1) specimen is very thin (<20nm) and
 - (2) the EDS scattering potential is highly localized.
- ➔ Fit the x-ray counts from the atomic column with a Gaussian function

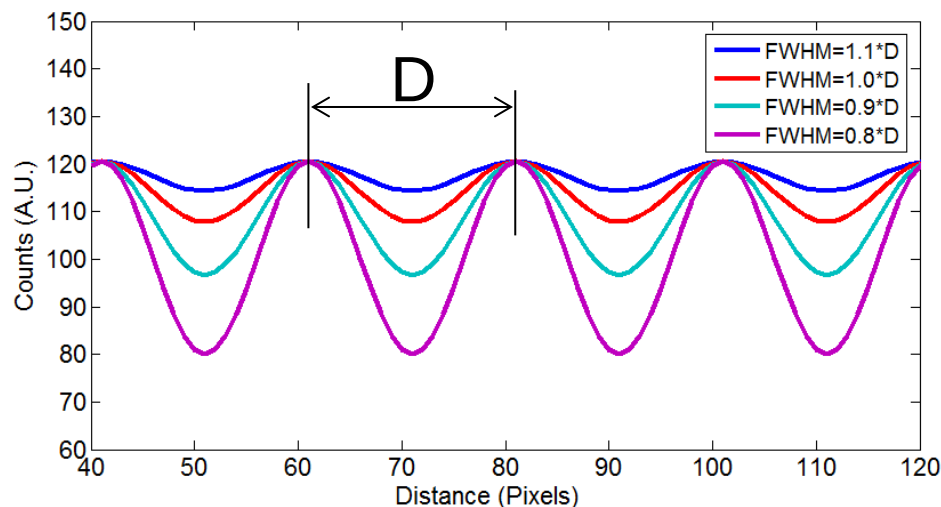
Spatial Resolution of Chemical Mapping

- The shortest lateral distance between same type of atoms in the projection



→ ~0.346 nm to resolve all atomic columns in this projection

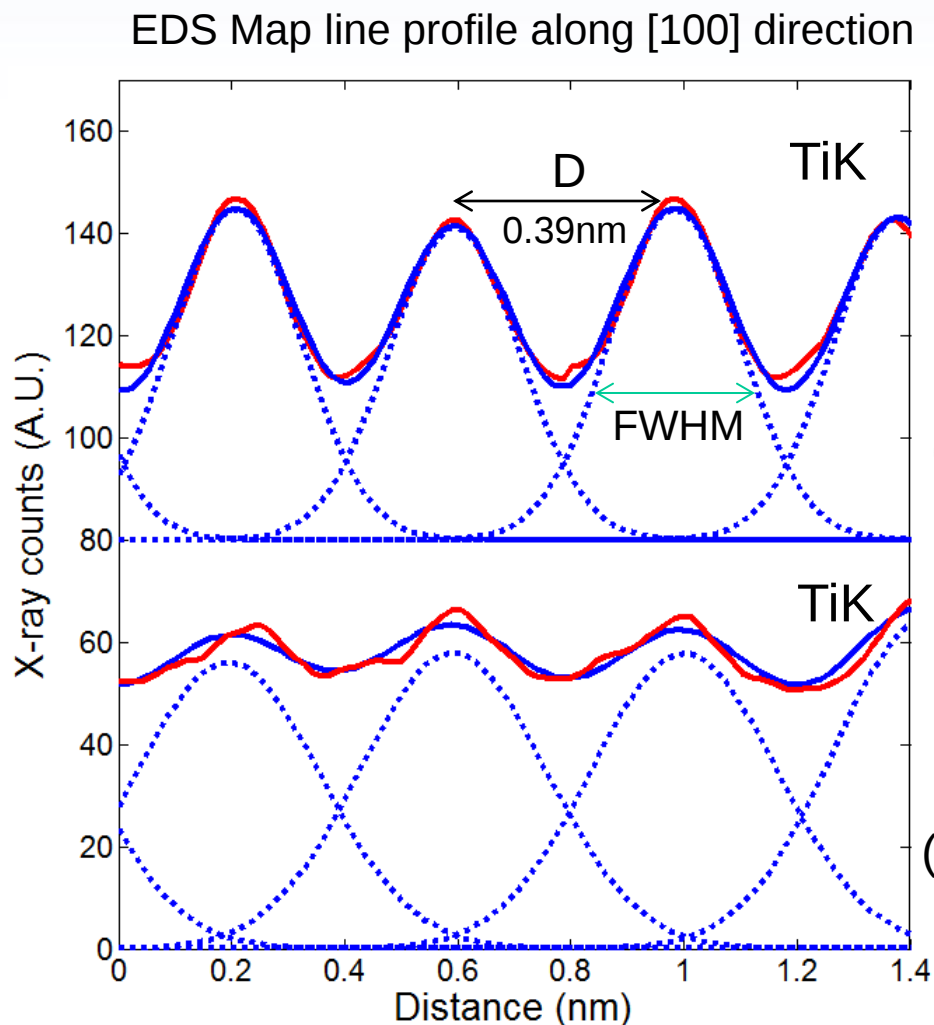
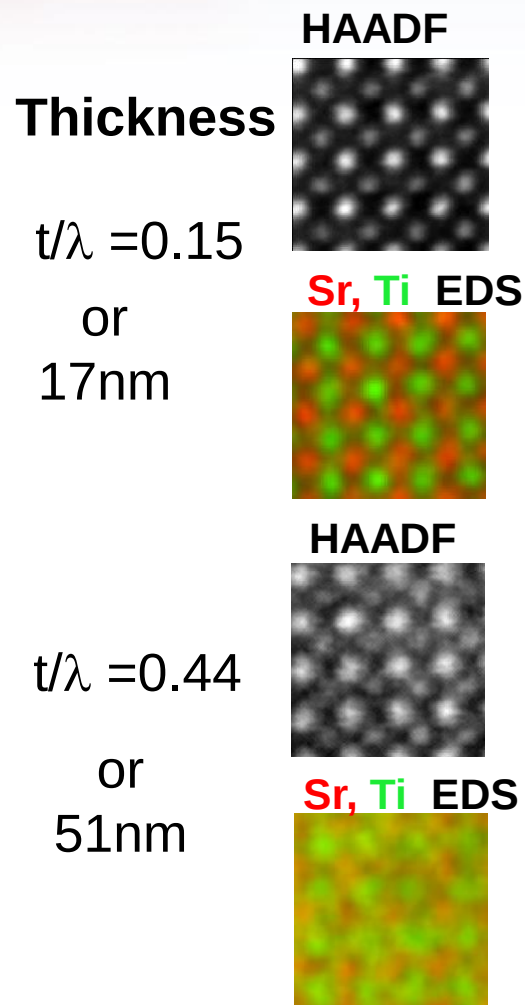
- The FWHM of the Gaussian peak vs Spatial resolution



If $\Delta S/N > 3$

$\text{FWHM} < 0.86D$

Effect of specimen thickness



FWHM:
0.263 nm
(FWHM/D = 0.67)

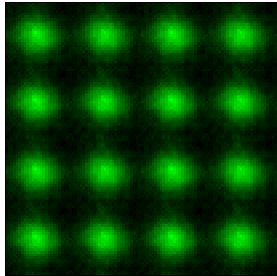
FWHM:
0.374 nm
(FWHM/D = 0.95)

➔ The thinner specimen, the better for the quantification

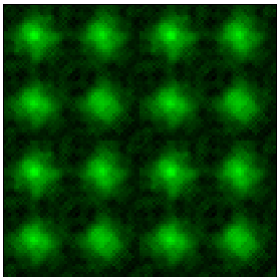
Effect of X-ray energy, TiK vs TiL

$$t/\lambda = 0.15$$

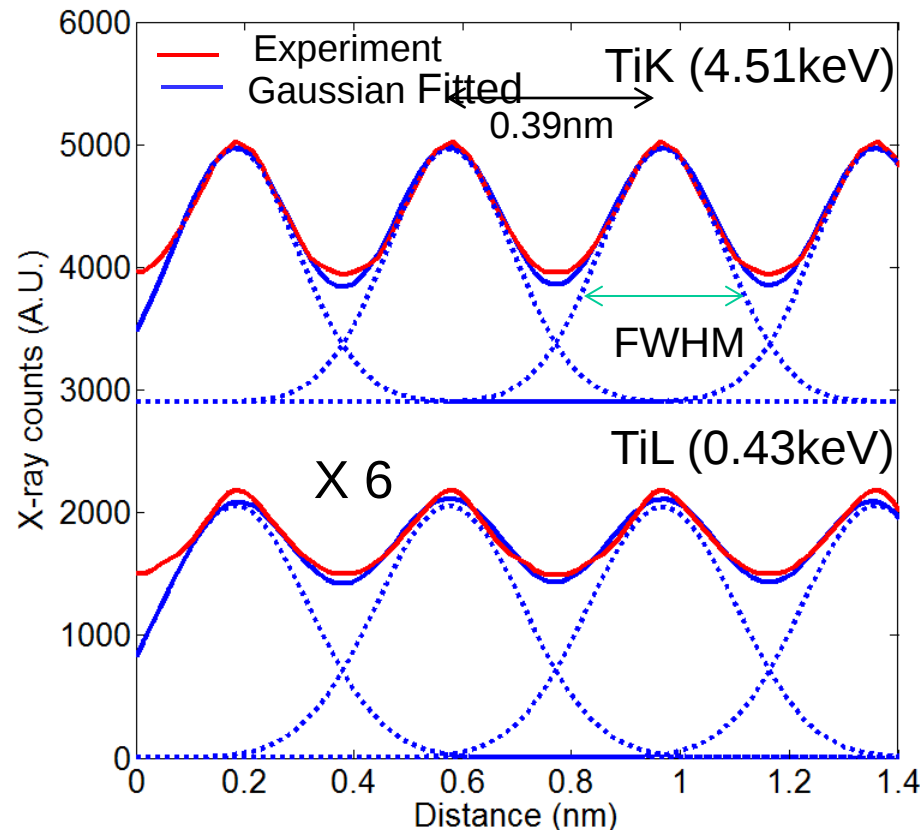
Ti K map



Ti L map



EDS Map line profile along [100] direction

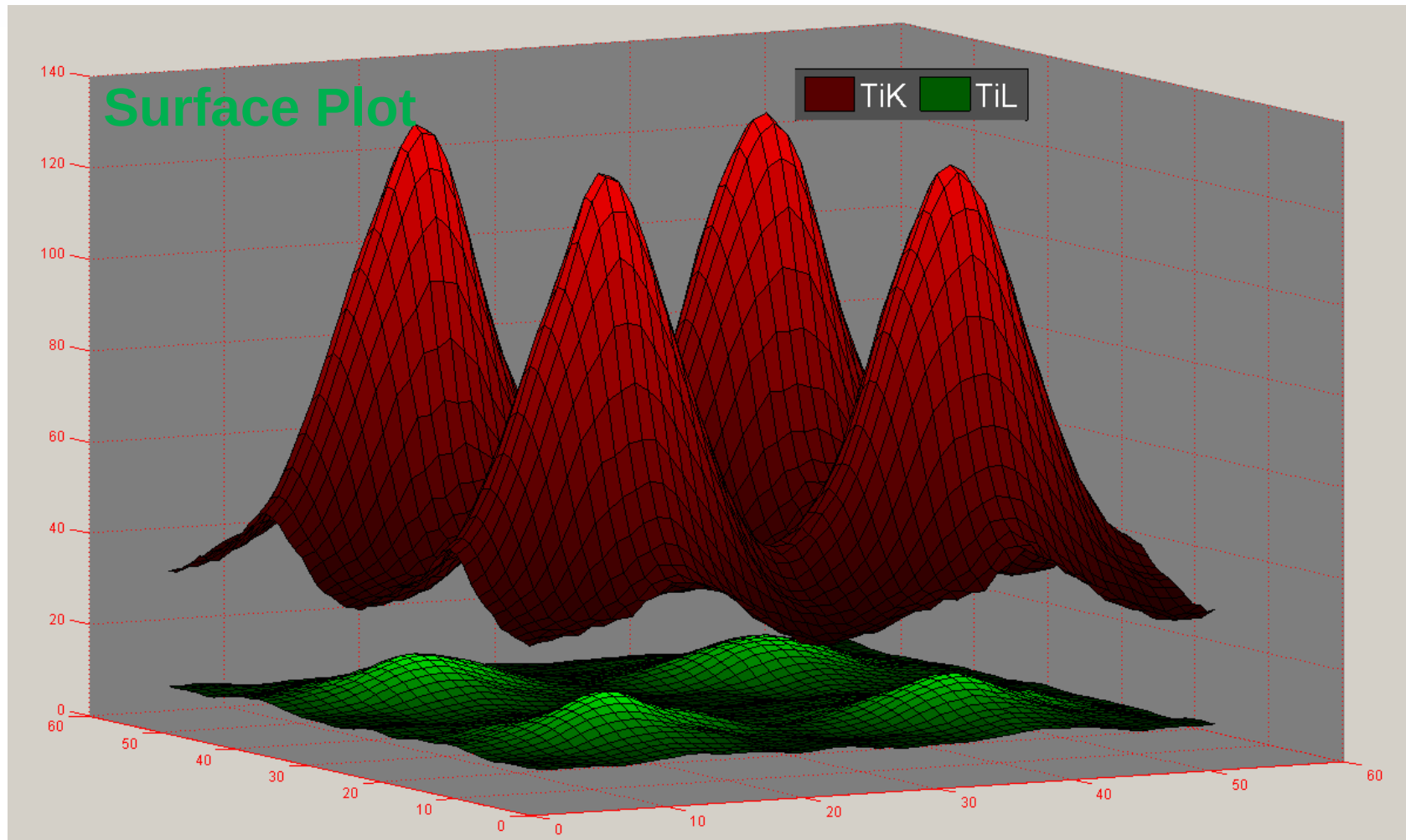


FWHM:
0.266 nm
(FWHM/D = 0.68)

FWHM:
0.317 nm
(FWHM/D = 0.813)

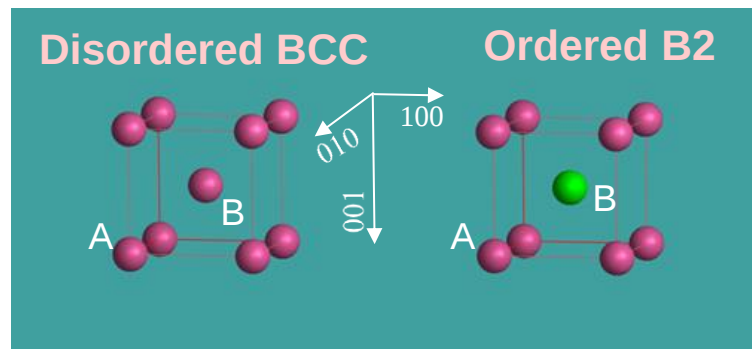
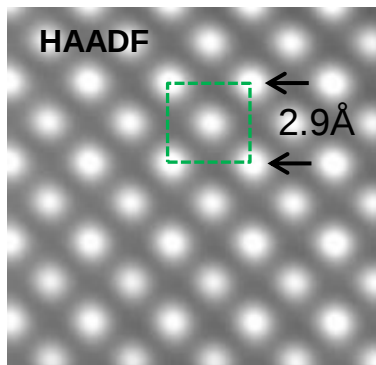
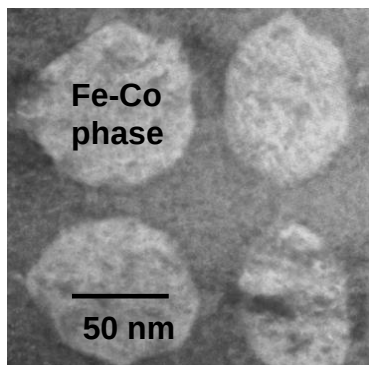
➔ The ionization potentials become less localized as the energy of the ejected electron decreases to below 1kV.

Effect of X-ray energy, TiK vs TiL

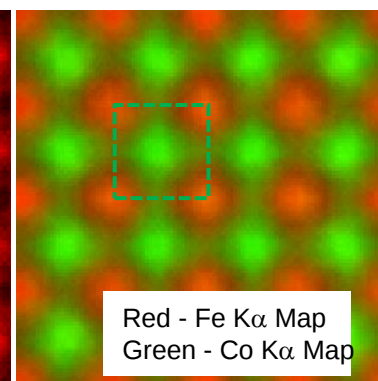
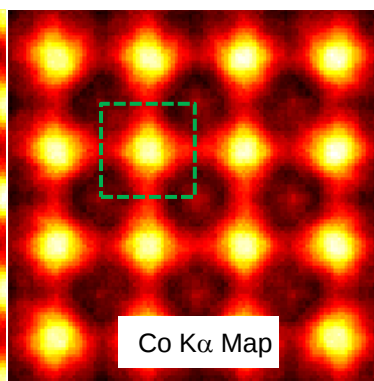
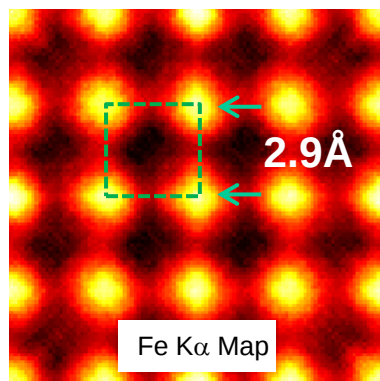


Example 1- Ordering-disordering in Fe-Co intermetallic phase

Fe-Co phase of an “alnico” alloy from a spinodal decomposition

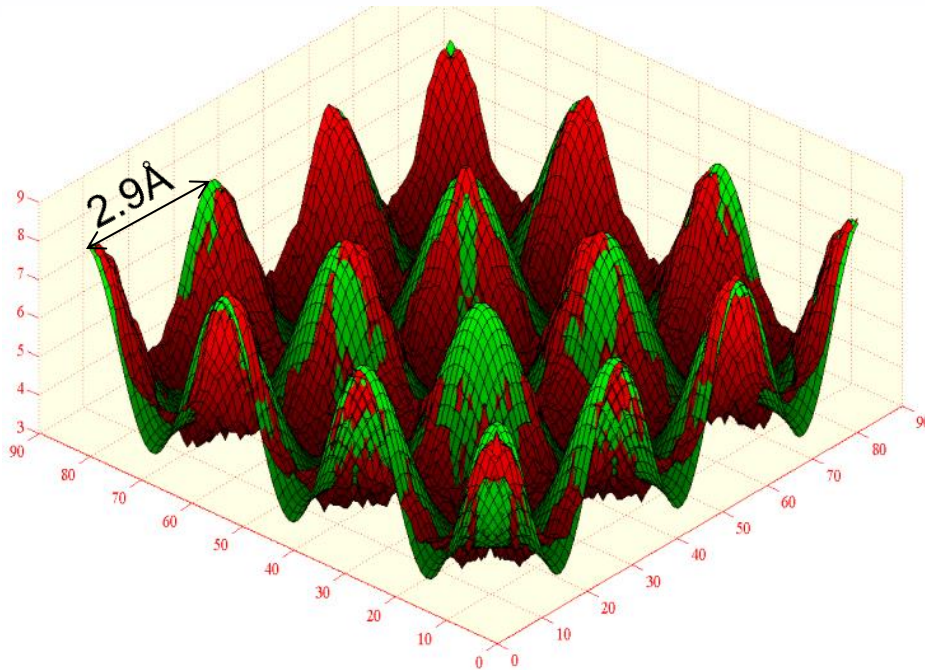


“Permanent magnet alloys”



Ordering-disordering in Fe-Co intermetallic phase

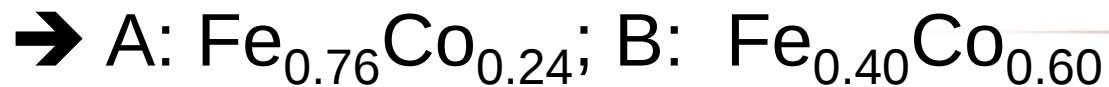
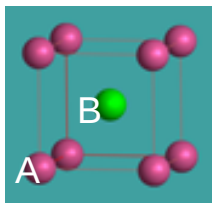
3-D surface plot for Fe K_{α}



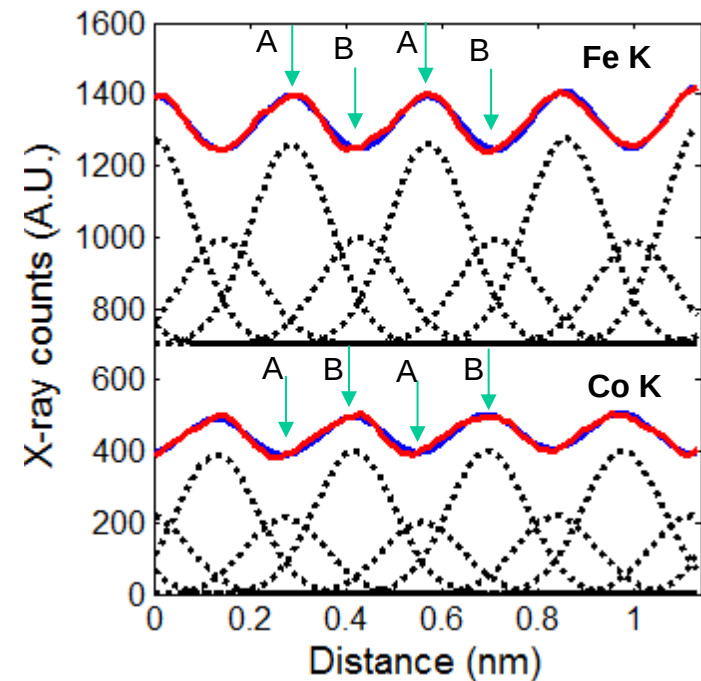
Red – experimental

Green – Gaussian fitted

(a constrained nonlinear optimization routine)



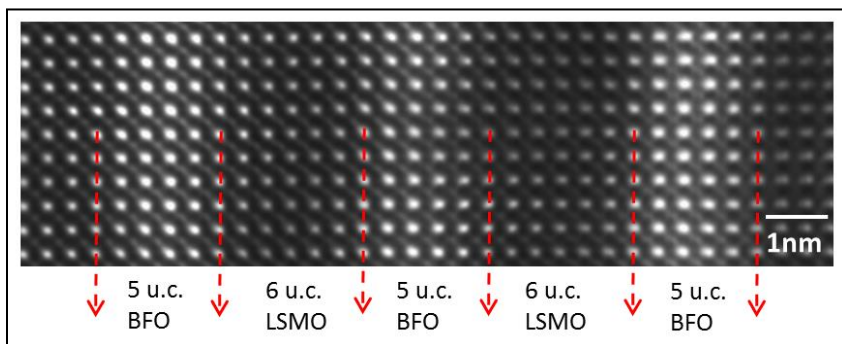
Line-profile in [100]



Example 2- $\text{La}_{0.7}\text{Sr}_{0.3}\text{MnO}_3/\text{BiFeO}_3$ quantum structure

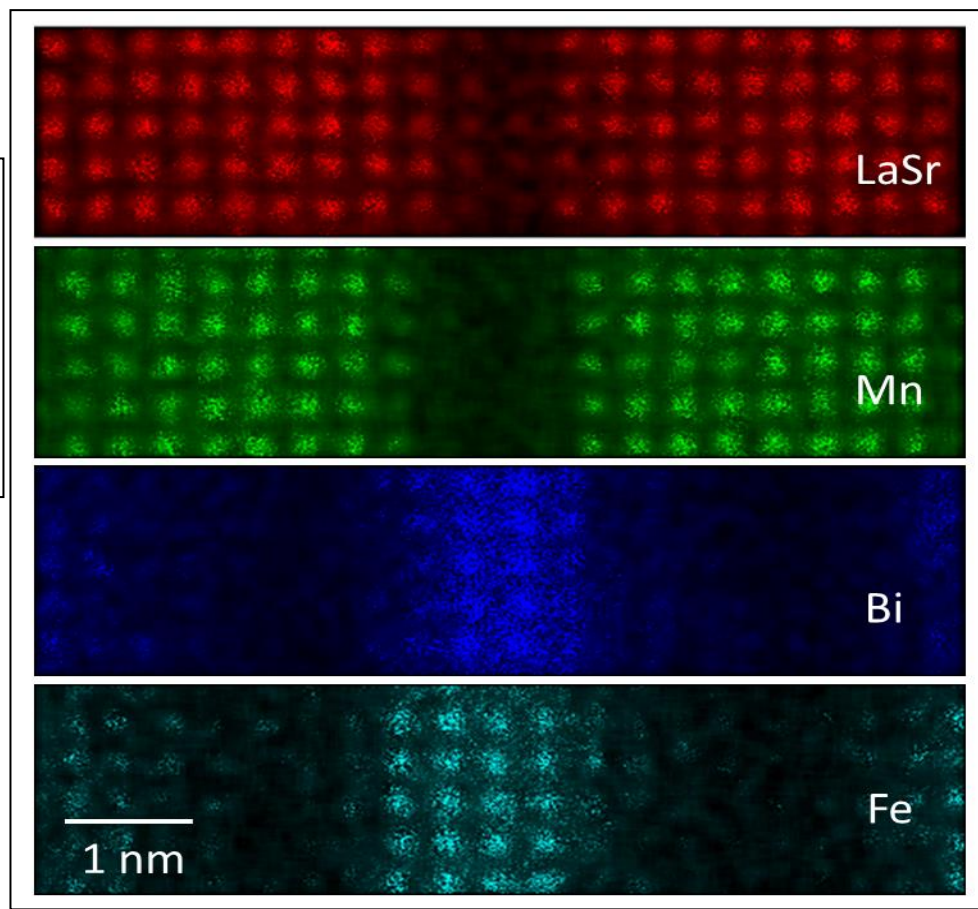
EDS Map

HAADF

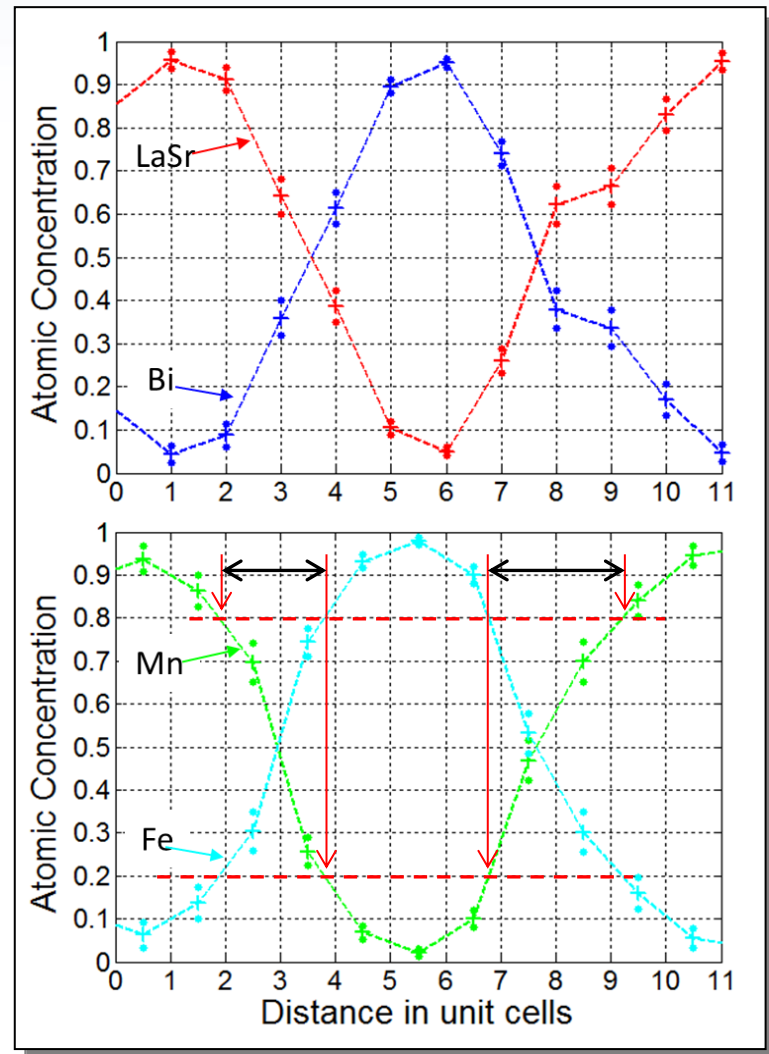
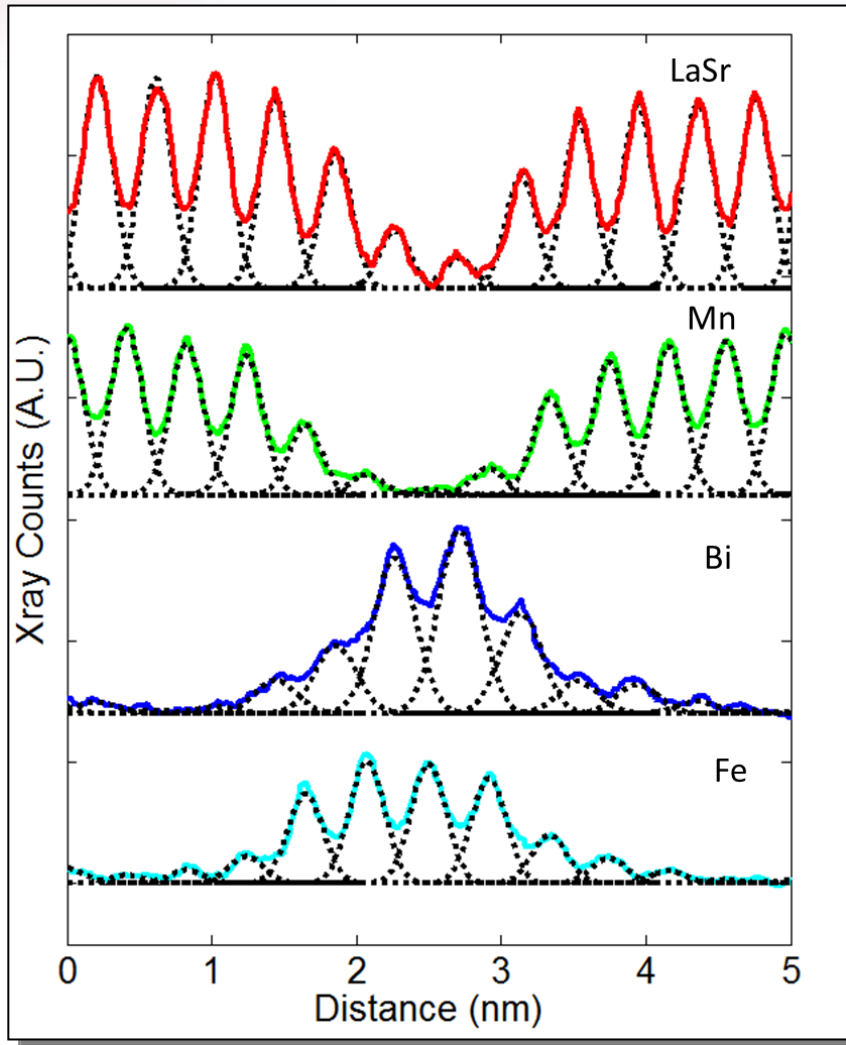


Pulsed Laser Deposition (PLD)
on STO

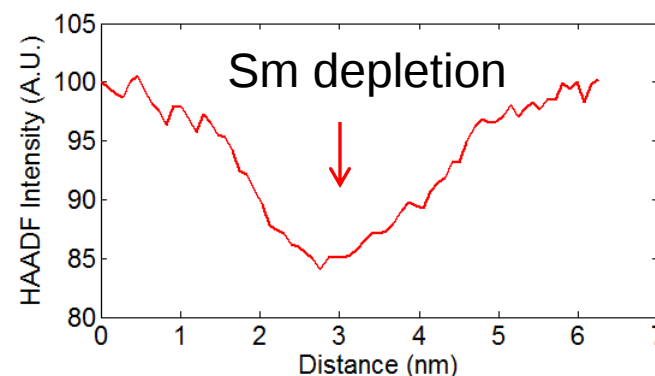
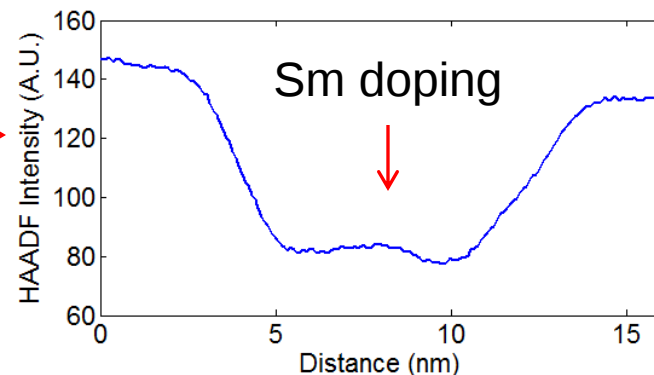
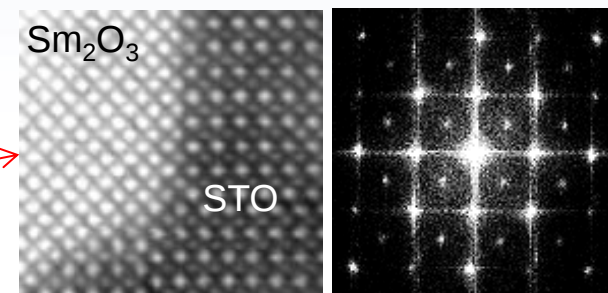
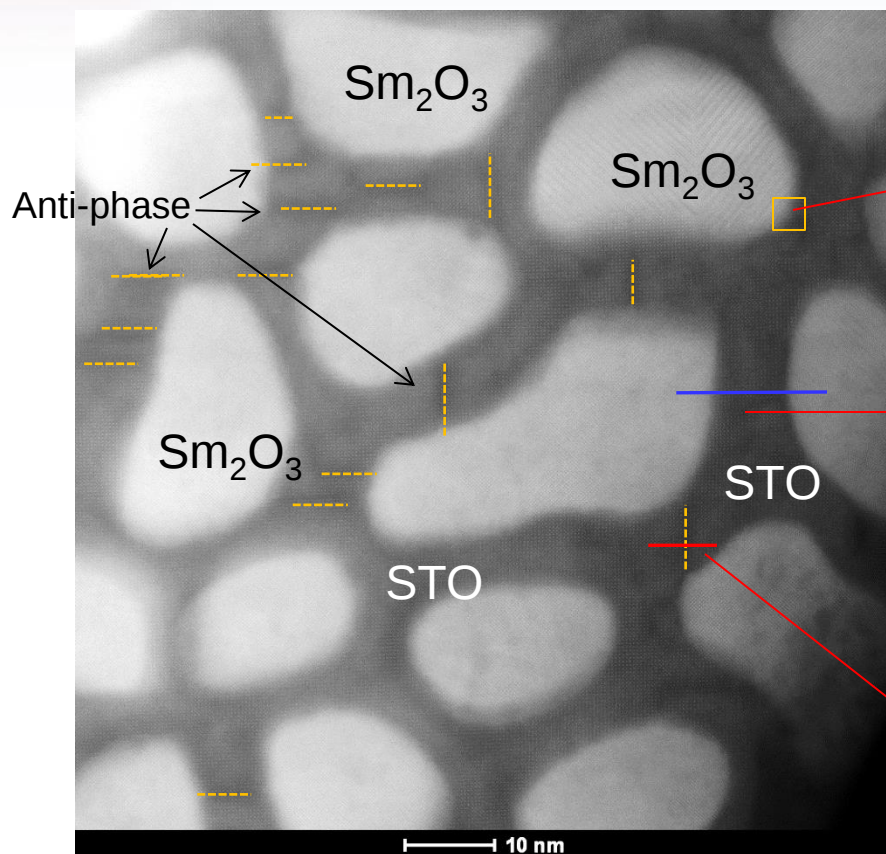
$\text{La}_{0.7}\text{Sr}_{0.3}\text{MnO}_3$ - Ferromagnetic
 BiFeO_3 - Antiferromagnetic



$\text{La}_{0.7}\text{Sr}_{0.3}\text{MnO}_3/\text{BiFeO}_3$ quantum structure



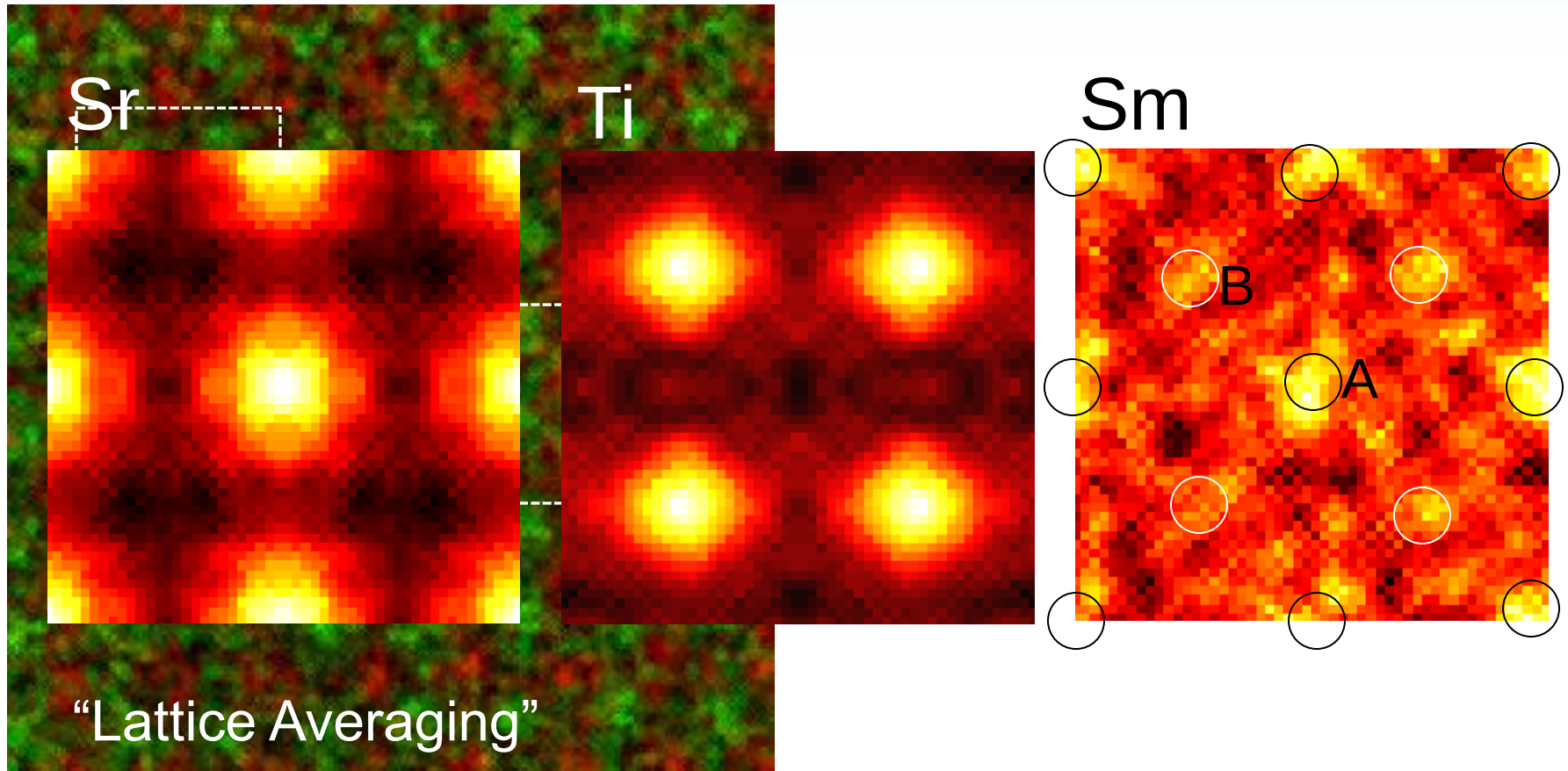
Example 3- Sm doping in SrTiO₃



Sm₂O₃ and SrTiO₃ co-deposited by PLD on STO substrate

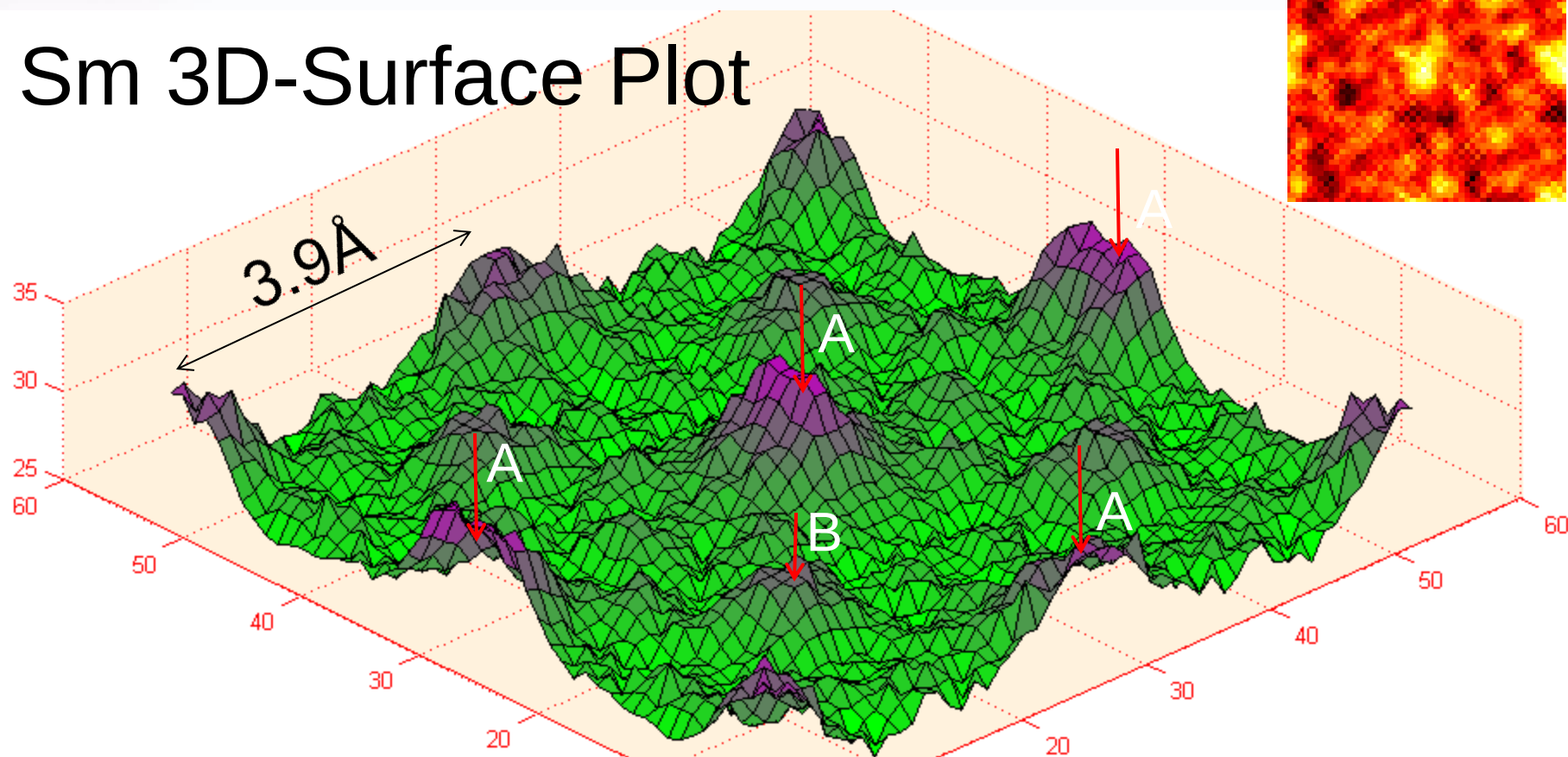
“Nanoscaffold memristor”

Sm doping in SrTiO_3

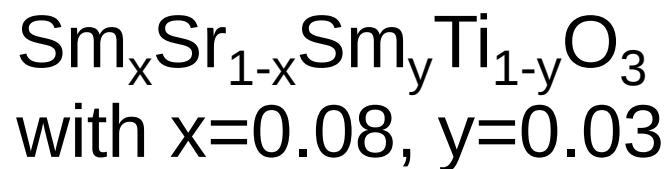


Lattice-Averaging can be used to improve S/N statistic!

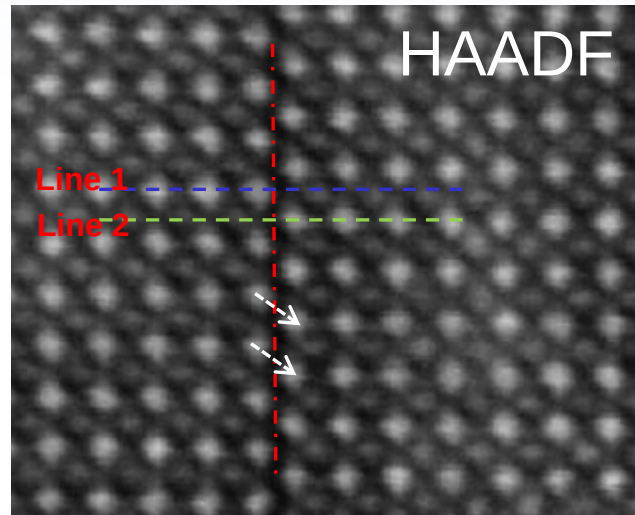
Sm 3D-Surface Plot



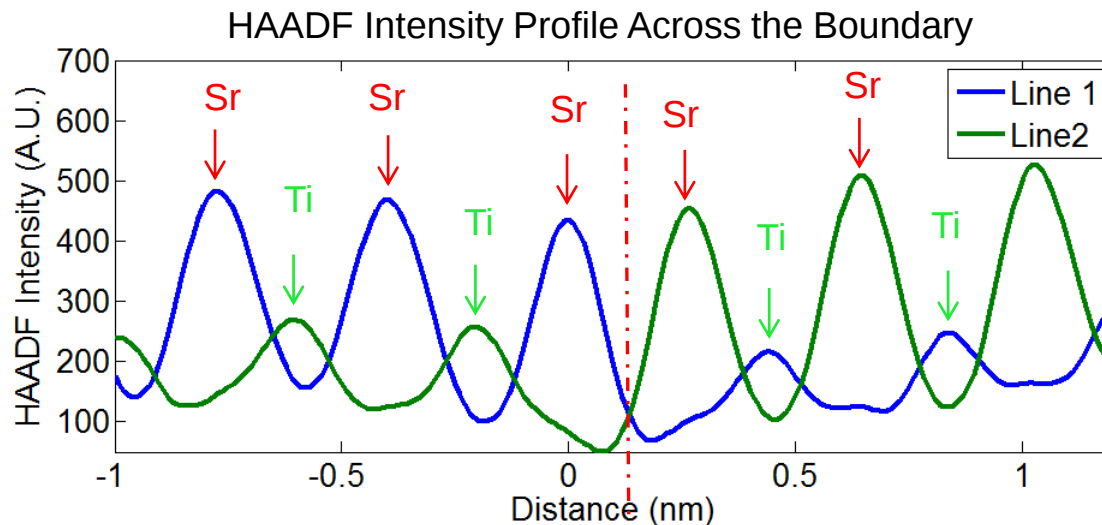
Sm atoms occupy both Sr and Ti sites, but preferentially Sr sites!



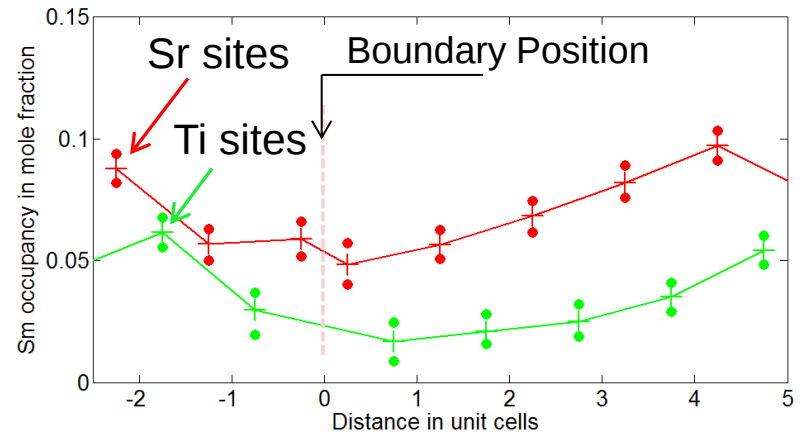
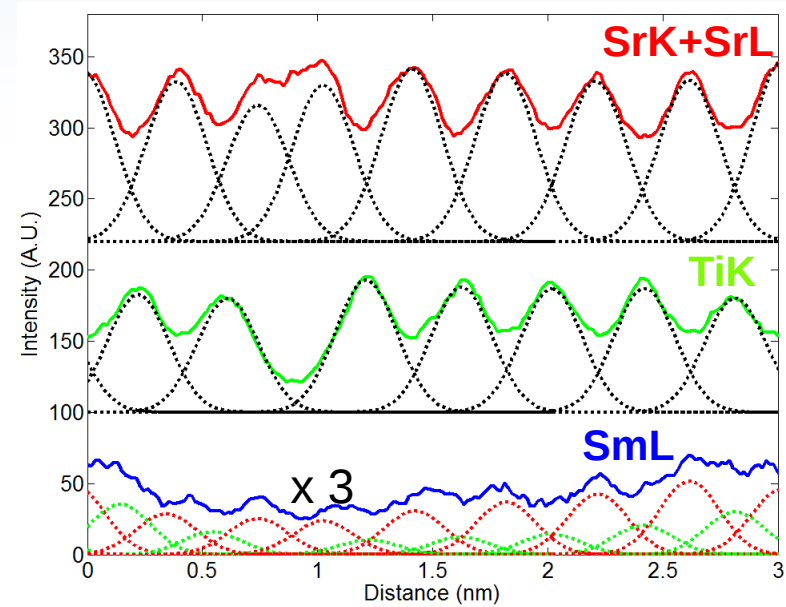
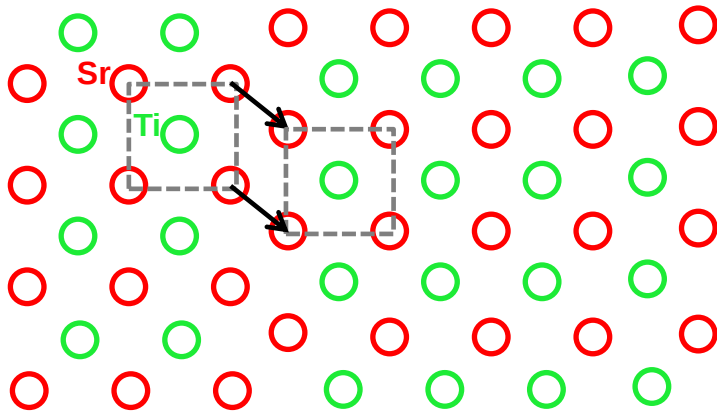
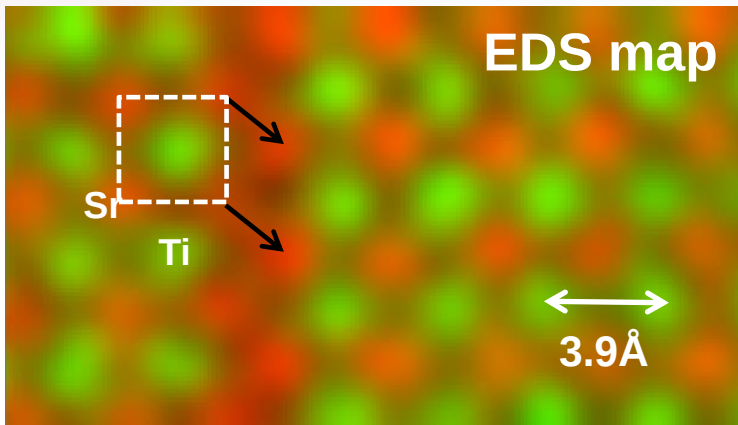
Anti-phase Boundaries



HAADF intensity decreases as it approaches the boundary!



Anti-phase Boundaries



- Sm atoms are depleted at the boundary!
- Likely, this is due to the strain effect.



Conclusions

- STEM-EDS maps can be properly quantified when specimen is thin and EDS scattering potential is localized such that the x-rays from each individual column is localized.
 - Thickness < 20 nm
 - X-ray energy > 1keV
 - Gaussian fitting the x-ray counts to account the x-rays from each atomic column and column-by-column quantification by Cliff-Lorimer method
- STEM-EDS provides a powerful approach to investigate structures chemically in real space at atomic-scale.
 - Ordering-disordering in a Fe-Co intermetallic (the technique developed in this study appears to be only way!)
 - Chemical quantification of oxide interfaces
 - Defect structure and doping concentration studies in oxide ceramics



Other collaborators:

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